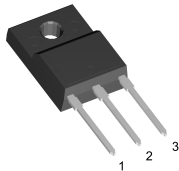
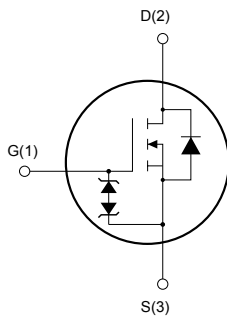


## N-channel 600 V, 0.255 $\Omega$ typ., 13 A MDmesh M2 Power MOSFET in a TO-220FP wide creepage package



TO-220FP wide creepage



AM15572v1\_no\_tab


**Product status link**
[STFH18N60M2](#)
**Product summary**

|                   |                        |
|-------------------|------------------------|
| <b>Order code</b> | STFH18N60M2            |
| <b>Marking</b>    | 18N60M2                |
| <b>Package</b>    | TO-220FP wide creepage |
| <b>Packing</b>    | Tube                   |

### Features

| Order code  | $V_{DS} @ T_{Jmax}$ | $R_{DS(on)}$ max. | $I_D$ |
|-------------|---------------------|-------------------|-------|
| STFH18N60M2 | 650 V               | 0.280 $\Omega$    | 13 A  |

- Extremely low gate charge
- Excellent output capacitance ( $C_{OSS}$ ) profile
- 100% avalanche tested
- Zener-protected
- Wide distance of 4.25 mm between the pins

### Applications

- Switching applications
- LCC converters
- Resonant converters

### Description

This device is an N-channel Power MOSFET developed using MDmesh M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

The TO-220FP wide creepage package provides increased surface insulation for Power MOSFETs to prevent failure due to arcing, which can occur in polluted environments.

# 1 Electrical ratings

**Table 1. Absolute maximum ratings**

| Symbol         | Parameter   | Value      | Unit             |
|----------------|---|------------|------------------|
| $V_{GS}$       | Gate-source voltage   | $\pm 25$   | V                |
| $I_D^{(1)}$    | Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$  | 13         | A                |
|                | Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$   | 8          | A                |
| $I_{DM}^{(2)}$ | Drain current (pulsed)  | 52         | A                |
| $P_{TOT}$      | Total power dissipation at $T_C = 25\text{ }^\circ\text{C}$   | 25         | W                |
| $dv/dt^{(3)}$  | Peak diode recovery voltage slope   | 15         | V/ns             |
| $dv/dt^{(4)}$  | MOSFET $dv/dt$ ruggedness   | 50         | V/ns             |
| $V_{ISO}$      | Insulation withstand voltage (RMS) from all three leads to external heat sink ( $t = 1\text{ s}$ ; $T_C = 25\text{ }^\circ\text{C}$ ) | 2.5        | kV               |
| $T_{stg}$      | Storage temperature range   | -55 to 150 | $^\circ\text{C}$ |
| $T_j$          | Operating junction temperature range  |            |                  |

- Limited by maximum junction temperature.
- Pulse width limited by safe operating area.
- $I_{SD} \leq 13\text{ A}$ ,  $di/dt \leq 400\text{ A}/\mu\text{s}$ ;  $V_{DS(peak)} < V_{(BR)DSS}$ ,  $V_{DD} = 400\text{ V}$
- $V_{DS} \leq 480\text{ V}$

**Table 2. Thermal data**

| Symbol         | Parameter                           | Value | Unit                      |
|----------------|-------------------------------------|-------|---------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case    | 5     | $^\circ\text{C}/\text{W}$ |
| $R_{thj-amb}$  | Thermal resistance junction-ambient | 62.5  | $^\circ\text{C}/\text{W}$ |

**Table 3. Avalanche characteristics**

| Symbol   | Parameter  | Value | Unit |
|----------|--|-------|------|
| $I_{AR}$ | Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax}$ )                                 | 3     | A    |
| $E_{AS}$ | Single pulse avalanche energy (starting $T_j = 25\text{ }^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ ) | 135   | mJ   |

## 2 Electrical characteristics

( $T_C = 25\text{ °C}$  unless otherwise specified).

**Table 4. On /off states**

| Symbol        | Parameter                         | Test conditions   | Min. | Typ.  | Max.     | Unit          |
|---------------|-----------------------------------|---|------|-------|----------|---------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage    | $I_D = 1\text{ mA}, V_{GS} = 0\text{ V}$                                | 600  |       |          | V             |
| $I_{DSS}$     | Zero gate voltage drain current   | $V_{GS} = 0\text{ V}, V_{DS} = 600\text{ V}$                            |      |       | 1        | $\mu\text{A}$ |
|               |                                   | $V_{GS} = 0\text{ V}, V_{DS} = 600\text{ V}, T_C = 125\text{ °C}^{(1)}$ |      |       | 100      | $\mu\text{A}$ |
| $I_{GSS}$     | Gate-body leakage current         | $V_{DS} = 0\text{ V}, V_{GS} = \pm 25\text{ V}$                         |      |       | $\pm 10$ | $\mu\text{A}$ |
| $V_{GS(th)}$  | Gate threshold voltage            | $V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$                         | 2    | 3     | 4        | V             |
| $R_{DS(on)}$  | Static drain-source on-resistance | $V_{GS} = 10\text{ V}, I_D = 6.5\text{ A}$                              |      | 0.255 | 0.280    | $\Omega$      |

1. Defined by design, not subject to production test.

**Table 5. Dynamic**

| Symbol                     | Parameter                     | Test conditions   | Min. | Typ.  | Max. | Unit     |
|----------------------------|-------------------------------|---|------|-------|------|----------|
| $C_{iss}$                  | Input capacitance             | $V_{DS} = 100\text{ V}, f = 1\text{ MHz}, V_{GS} = 0\text{ V}$  | -    | 791   | -    | pF       |
| $C_{oss}$                  | Output capacitance            |   | -    | 40    | -    | pF       |
| $C_{rSS}$                  | Reverse transfer capacitance  |   | -    | 1.3   | -    | pF       |
| $C_{oss\text{ eq.}}^{(1)}$ | Equivalent output capacitance | $V_{DS} = 0\text{ to }480\text{ V}, V_{GS} = 0\text{ V}$  | -    | 164.5 | -    | pF       |
| $R_G$                      | Intrinsic gate resistance     | $f = 1\text{ MHz}, I_D = 0\text{ A}$  | -    | 5.6   | -    | $\Omega$ |
| $Q_g$                      | Total gate charge             | $V_{DD} = 480\text{ V}, I_D = 13\text{ A}, V_{GS} = 0\text{ to }10\text{ V}$ (see Figure 14. Test circuit for gate charge behavior) | -    | 21.5  | -    | nC       |
| $Q_{gs}$                   | Gate-source charge            |   | -    | 3.2   | -    | nC       |
| $Q_{gd}$                   | Gate-drain charge             |   | -    | 11.3  | -    | nC       |

1.  $C_{oss\text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

**Table 6. Switching times**

| Symbol       | Parameter           | Test conditions   | Min. | Typ. | Max. | Unit |
|--------------|---------------------|---|------|------|------|------|
| $t_{d(on)}$  | Turn-on delay time  | $V_{DD} = 300\text{ V}, I_D = 6.5\text{ A}, R_G = 4.7\text{ }\Omega, V_{GS} = 10\text{ V}$<br>(see Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform) | -    | 12   | -    | ns   |
| $t_r$        | Rise time           |   | -    | 9    | -    | ns   |
| $t_{d(off)}$ | Turn-off delay time |   | -    | 47   | -    | ns   |
| $t_f$        | Fall time           |   | -    | 10.6 | -    | ns   |

**Table 7. Source drain diode**

| Symbol          | Parameter                     | Test conditions  | Min. | Typ. | Max. | Unit          |
|-----------------|-------------------------------|--|------|------|------|---------------|
| $I_{SD}$        | Source-drain current          |  | -    |      | 13   | A             |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) |  | -    |      | 52   | A             |
| $V_{SD}^{(2)}$  | Forward on voltage            | $I_{SD} = 13\text{ A}$ , $V_{GS} = 0\text{ V}$   | -    |      | 1.6  | V             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 13\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$  | -    | 305  |      | ns            |
| $Q_{rr}$        | Reverse recovery charge       | $V_{DD} = 60\text{ V}$ (see Figure 15. Test circuit for inductive load switching and diode recovery times) | -    | 3.3  |      | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      | (see Figure 15. Test circuit for inductive load switching and diode recovery times)                        | -    | 22   |      | A             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 13\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$  | -    | 417  |      | ns            |
| $Q_{rr}$        | Reverse recovery charge       | $V_{DD} = 60\text{ V}$ , $T_j = 150\text{ }^\circ\text{C}$   | -    | 4.6  |      | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      | (see Figure 15. Test circuit for inductive load switching and diode recovery times)                        | -    | 22   |      | A             |

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

## 2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

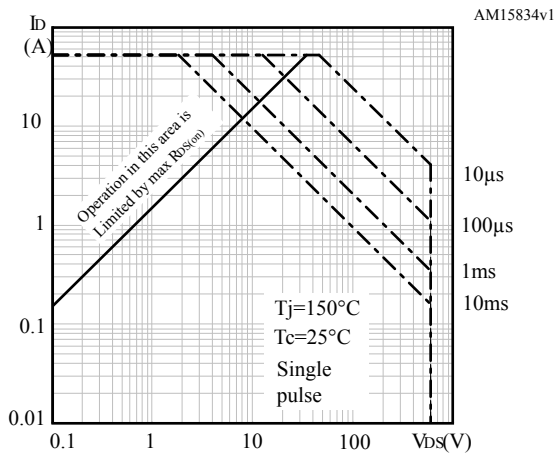


Figure 2. Thermal impedance

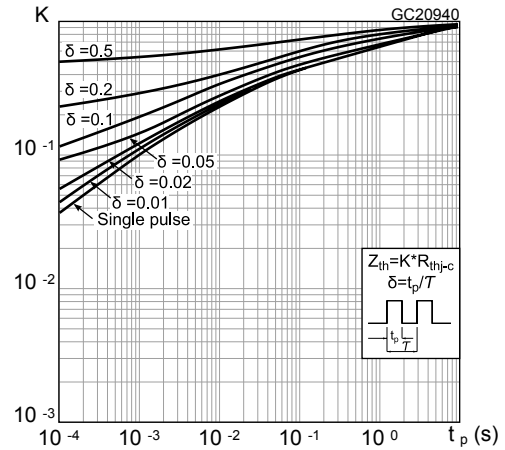


Figure 3. Output characteristics

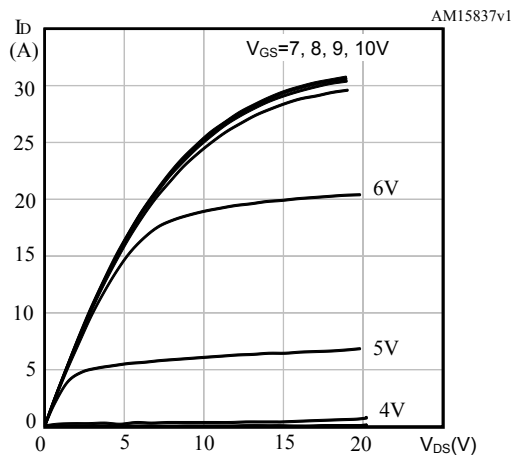


Figure 4. Transfer characteristics

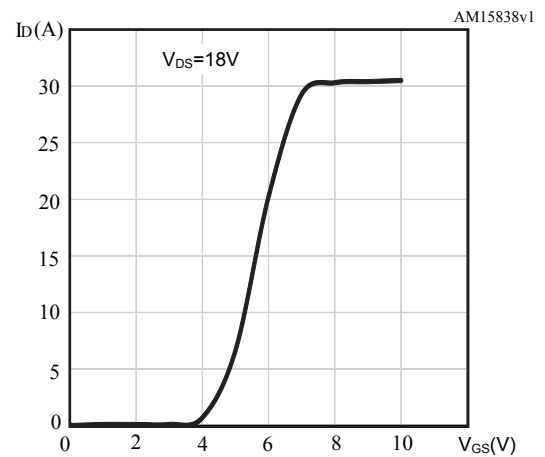


Figure 5. Gate charge vs gate-source voltage

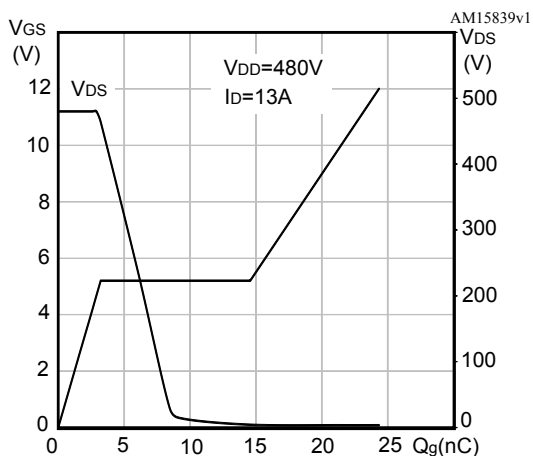


Figure 6. Static drain-source on-resistance

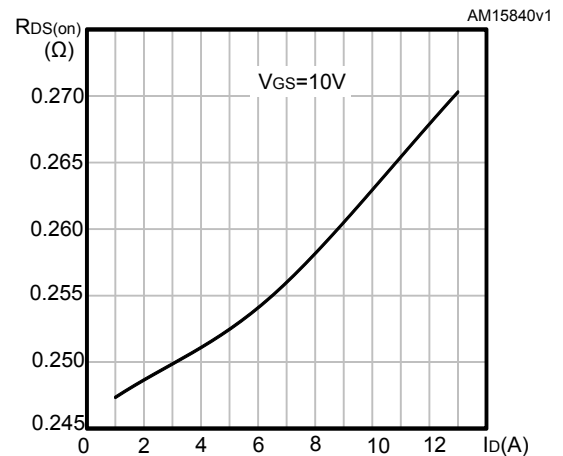


Figure 7. Capacitance variations

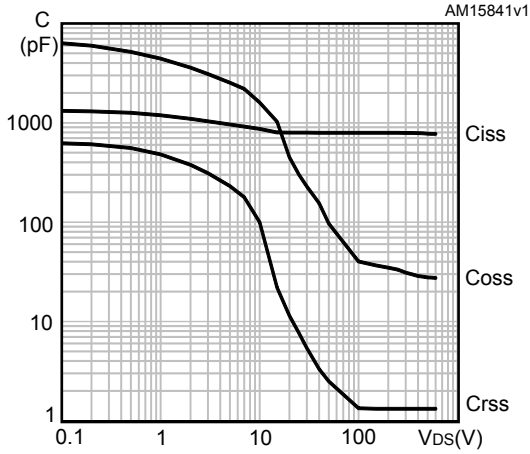


Figure 8. Normalized gate threshold voltage vs. temperature

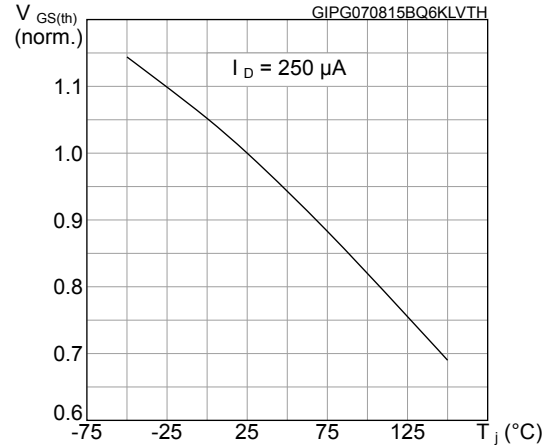


Figure 9. Normalized on-resistance vs temperature

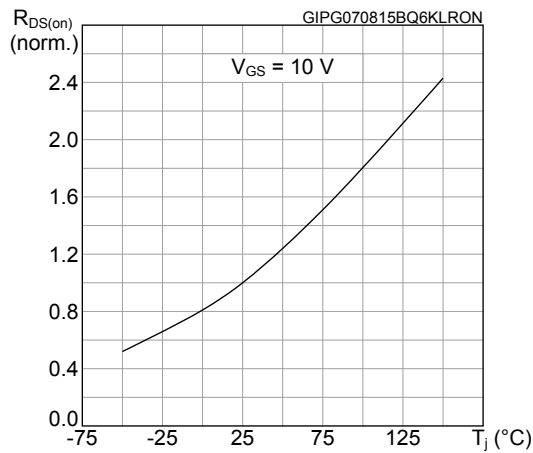


Figure 10. Source-drain diode forward characteristics

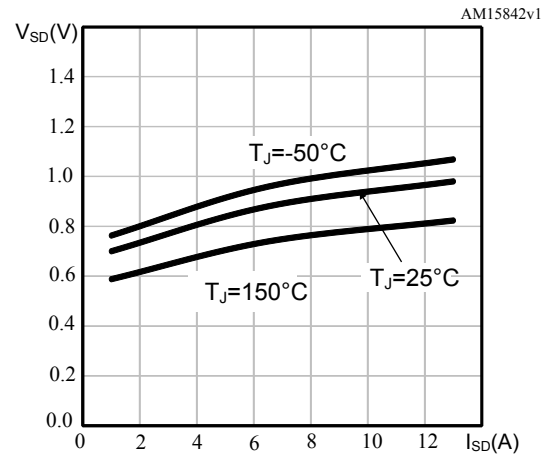


Figure 11. Normalized  $V_{(BR)DSS}$  vs temperature

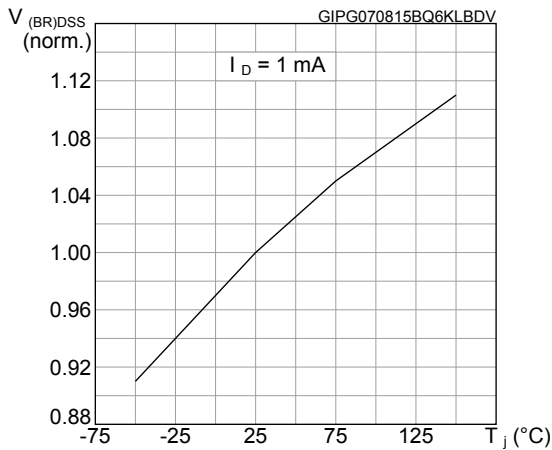
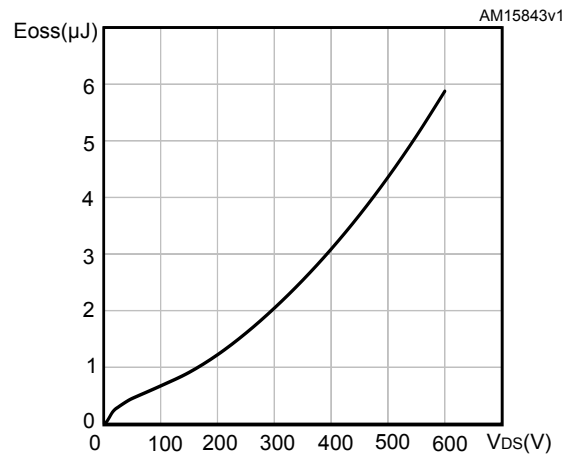
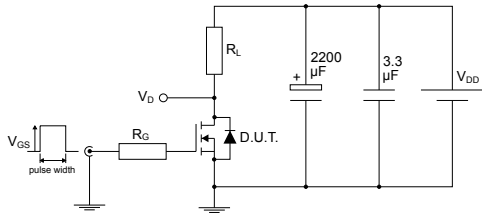


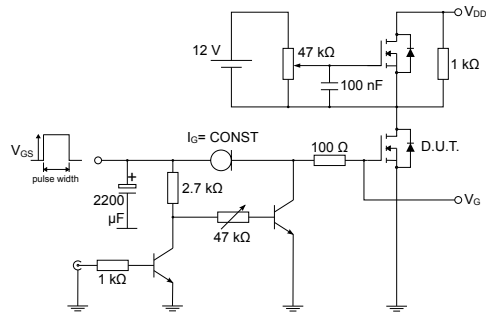
Figure 12. Output capacitance stored energy



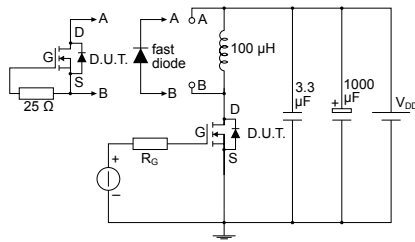
### 3 Test circuits

**Figure 13. Test circuit for resistive load switching times**


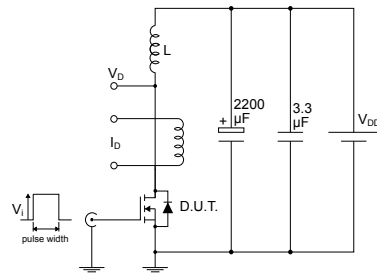
AM01468v1

**Figure 14. Test circuit for gate charge behavior**


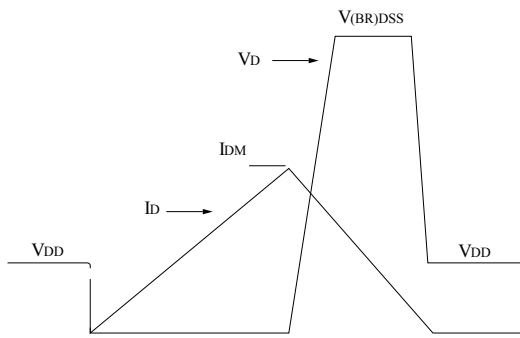
AM01469v1

**Figure 15. Test circuit for inductive load switching and diode recovery times**


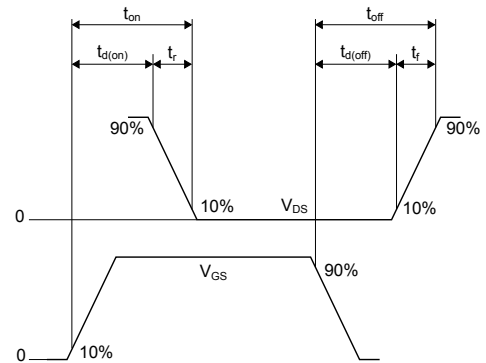
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**Figure 16. Unclamped inductive load test circuit**


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**Figure 17. Unclamped inductive waveform**


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**Figure 18. Switching time waveform**


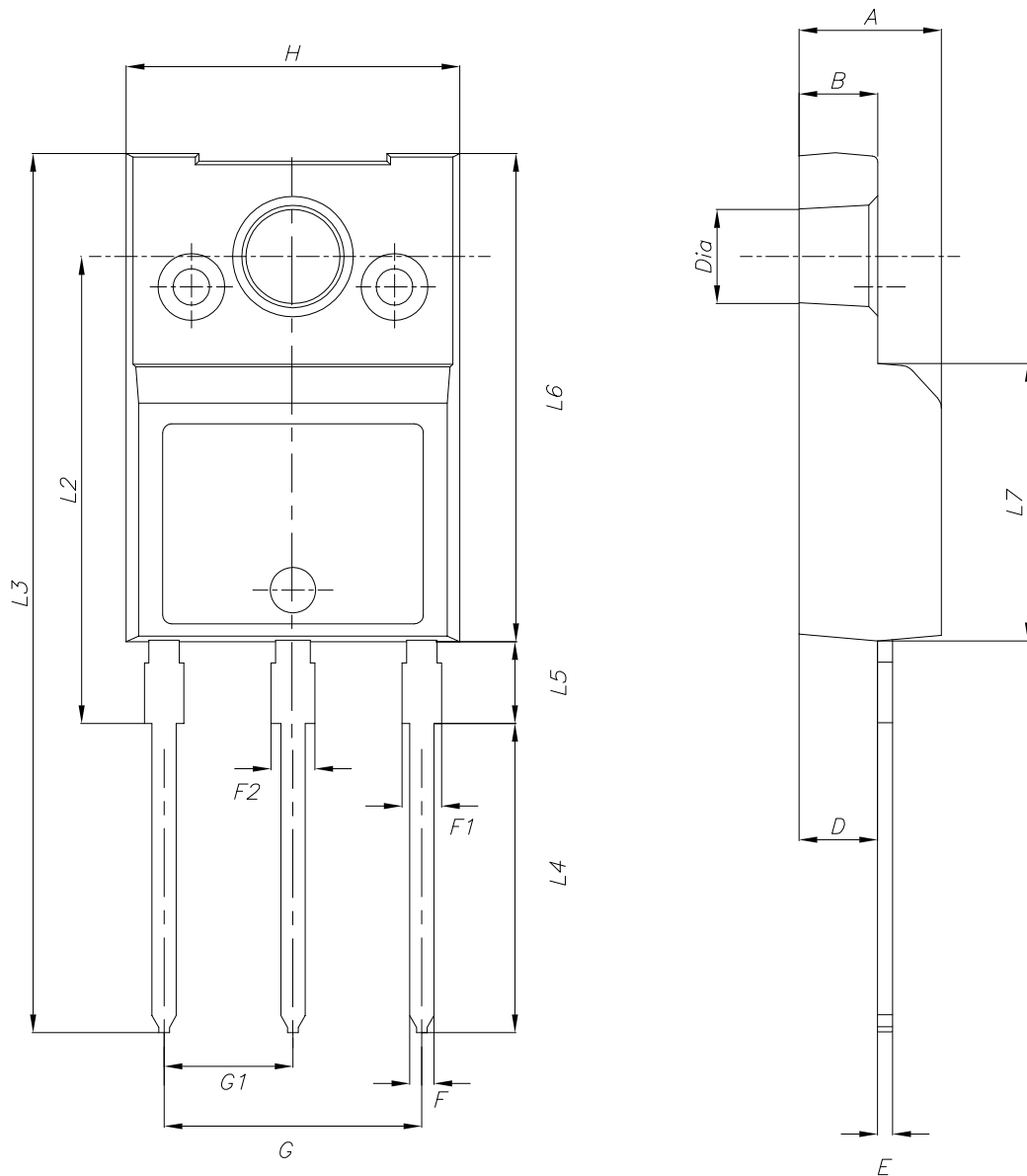
AM01473v1

## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

### 4.1 TO-220FP wide creepage package information

Figure 19. TO-220FP wide creepage package outline



DM00260252\_1



**Table 8. TO-220FP wide creepage package mechanical data**

| Dim. | mm    |       |       |
|------|-------|-------|-------|
|      | Min.  | Typ.  | Max.  |
| A    | 4.60  | 4.70  | 4.80  |
| B    | 2.50  | 2.60  | 2.70  |
| D    | 2.49  | 2.59  | 2.69  |
| E    | 0.46  |       | 0.59  |
| F    | 0.76  |       | 0.89  |
| F1   | 0.96  |       | 1.25  |
| F2   | 1.11  |       | 1.40  |
| G    | 8.40  | 8.50  | 8.60  |
| G1   | 4.15  | 4.25  | 4.35  |
| H    | 10.90 | 11.00 | 11.10 |
| L2   | 15.25 | 15.40 | 15.55 |
| L3   | 28.70 | 29.00 | 29.30 |
| L4   | 10.00 | 10.20 | 10.40 |
| L5   | 2.55  | 2.70  | 2.85  |
| L6   | 16.00 | 16.10 | 16.20 |
| L7   | 9.05  | 9.15  | 9.25  |
| Dia  | 3.00  | 3.10  | 3.20  |

## Revision history

**Table 9. Document revision history**

| Date        | Revision | Changes  |
|-------------|----------|--|
| 08-Jun-2016 | 1        | First release.   |
| 16-Jun-2016 | 2        | Document status promoted from preliminary data to production data.<br>Minor text changes.  |
| 06-Jun-2019 | 3        | Modified Figure 8. Normalized gate threshold voltage vs. temperature, Figure 9. Normalized on-resistance vs temperature and Figure 11. Normalized $V_{(BR)DSS}$ vs temperature.<br>Minor text changes. |

## Contents

|            |   |           |
|------------|---|-----------|
| <b>1</b>   | <b>Electrical ratings</b> .....                         | <b>2</b>  |
| <b>2</b>   | <b>Electrical characteristics</b> .....                 | <b>3</b>  |
| <b>2.1</b> | <b>Electrical characteristics (curves)</b> .....        | <b>5</b>  |
| <b>3</b>   | <b>Test circuits</b> .....                              | <b>7</b>  |
| <b>4</b>   | <b>Package information</b> .....                        | <b>8</b>  |
| <b>4.1</b> | <b>TO-220FP wide creepage package information</b> ..... | <b>8</b>  |
|            | <b>Revision history</b> .....                           | <b>10</b> |

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